

TAIWAN TOKIN EMC ENG. CORP.

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TEST LAB.

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Technical Compliance Statement

No. ATM-E99193

The following products has been tested by us with the listed standards and found in compliance with the council EMC directive 89/336/EEC. It is possible to use CE marking to demonstrate the compliance with this EMC Directive.

Submittor

FSP Group Inc.

6F-1, No. 487, Ta-Yu Rd.,

Taoyuan City, Taiwan, R.O.C.

Product

Switching Power Supply

M/N (1)FSP250-60GIA (7)FSP200-60GIA

(2)FSP250-60GNA (8)FSP200-60GNA

(3)FSP250-60GTA

(9)FSP200-60GTA

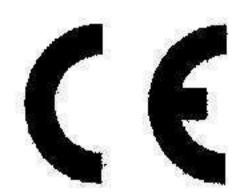
(4)FSP235-60GIA

(10)FSP145-60GIA (11)FSP145-60GNA

(5)FSP235-60GNA

(6)FSP235-60GTA (12)FSP145-60GTA

Test Standards		
EN 55022/1998	Limits and methods of measurement of radio disturbance characteristics of information technology equipment	
EN 60555-2/1987	Disturbances in supply systems caused by household appliances and similar electrical equipment Part 2: Specification of harmonics	
EN 61000-3-3/1995	Part 3: Limits-Section 3: Limitation of voltage fluctuations and flicker in low-voltage supply systems for equipment with rated current <=16A	
EN 55024/1998	Information technology equipment-Immunity characteristics Limits and methods of measurement	
	IEC 61000-4-2/1995	Electrostatic discharge immunity test
	IEC 61000-4-3/1995	Radiated, radio-frequency electromagnetic field immunity test
	IEC 61000-4-4/1995	Electrical fast transient / burst immunity test
	IEC 61000-4-5/1995	Surge immunity test
	IEC 61000-4-6/1996	Immunity to conducted disturbances, induced by radio-frequency fields
3.	IEC 61000-4-11/1994	Voltage dips, short interruptions and voltage variations immunity test



Shelene Hou Assistant Manager

The verification is based on a single evaluation of one sample of above mentioned products. It does not imply an assessment of the whole production and does not permit the use of the test lab. logo.